nexperia

Quarterly Reliability Monitoring Results

Quarters: Q1/2021 to Q4/2021

| Based on structural similarity |
|--------------------------------|
|--------------------------------|

| Supplier Nexperia B.V. | | User Part Number | | | | | |
|---------------------------|---|---|-------------|-----------|------------|-----------|--|
| | | PMEG2005EL | | | | | |
| Name of Laboratory | | Part Description | | | | | |
| | | Nexperia DHAM | Schottky | | | | |
| Assembly reliability labs | | MCD package | | | | | |
| Based on <i>I</i> | AEC-Q101 Test | Test Conditions | Duration | # Lots | # Quantity | # Rejects | |
| | TEST | | | | | | |
| | Pre- and Post-Stress Electrical Test | Tamb = 25 °C | N1 (A | | all wants | | |
| # E1 | | | N/A | see below | all parts | see below | |
| | | JESD22-A113 Bake Tamb = 125 °C | 24 hours | | | | |
| | PC | Soak Tamb = 85 °C, RH = 85% | 168 hours | | | | |
| # A1 | Preconditioning | Reflow soldering | 3 cycles | 113 | 9040 | 0 | |
| | | MIL-STD-750-1 | | | | | |
| | HTRB | M1038 Method A | | | | | |
| | High Temperature Reverse | Tj = Tjmax, $Vr = 100%$ of max. datasheet | | | | | |
| # B1 | Bias | reverse voltage ^[1] | 1000 hours | 116 | 9280 | 0 | |
| | | | | | | | |
| | TC | JESD22-A104 | | | | | |
| # A4 | Temperature Cycling | -65 °C to Tjmax, not to exceed 150°C | 1000 cycles | 28 | 2240 | 0 | |
| | AC | JESD22-A102 | | | | | |
| # A3 alt | AL Autoclave | Tamb = 121 °C, RH = 100 % Pressure = 205 kPa (29.7 psia) | 96 hours | 28 | 2240 | 0 | |
| # A5 dit | Autoclave | | 96 hours | 28 | 2240 | U | |
| | H3TRB | JESD22-A101 | | | | | |
| | High Humidity High | Tamb = 85 °C, RH = 85%, VR = 80 % of | | | | | |
| # A2 alt | | rated reverse voltage ^{[1], [2]} | 1000 hours | 28 | 2240 | 0 | |
| | | MIL-STD-750 Method 1037 | | | | | |
| | IOL | ton = toff, devices powered to insure ΔTj = | | | | | |
| # A5 | Intermittent Operating Life | 100 °C for 15000 cycles | 1000 hours | 29 | 2320 | 0 | |
| | | | | | | | |
| | RSH | JESD22-A111 | | | | | |
| # C8 | Resistance to Solder Heat | 260 °C ± 5 °C | 10 s | n.a. | n.a. | n.a. | |
| | SD | 1 075 000 | | | | | |
| # C10 | Solderability | J-STD-002 | | 63 | 630 | 0 | |

[1] The physical limitations of Schottky diodes have to be considered (thermal runaway).

[2] The maximum applied voltage is limited by test chamber set up and does not exceed 115V.

Calculation of FIT and MTTF

Test considered for FIT calculation: High Temperature Reverse Bias (HTRB, Test #B1)

Confidence level 60%, derated to 55 °C, activation energy 0.7 eV, test time 168 to 1000 hours

| Nexperia | |
|---------------------------|----------|
| DUAM | |
| DHAM Schottky 9280 0 0.46 | 2.19E+09 |

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